

DR-21. INVESTIGATION OF ZINC SELENIDE THIN FILMS PRODUCED BY CHEMICAL BATH DEPOSITION

A. A. Timina¹, L. N. Maskaeva^{1,2}, V. F. Markov^{1,2}, K. A. Karpov¹

¹Ural Federal University of the first President of Russia B. N. Yeltsin,
Mira St., 19, Yekaterinburg, 620002, Russia

²Chemistry and Combustion Process Department,
Ural State Fire Service Institute of Emergency Ministry of Russia,
Mira St., 22, Yekaterinburg, 620022, Russia

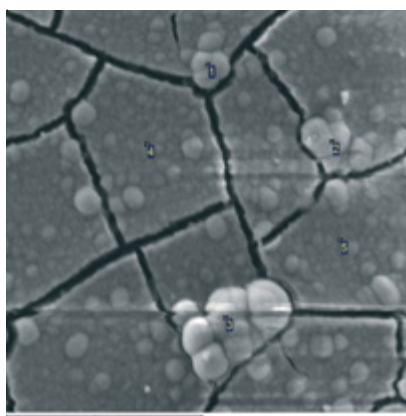
E-mail: aatimina@mail.ru

The most perspective from typical wide-band gap representors of semiconductor A^{II}B^{VI} compounds is zinc selenide. Zinc selenide can be used in creation of semiconductor electronic devices and information display systems, active laser medium, color TV screens, optical light modulators and other optoelectronic devices.

Many researchers prefer simple in technical performance method of chemical bath deposition from aqueous mediums to obtain selenide ZnSe thin films. Sodium selenosulfate Na₂SeSO₃ or selenourea N₂H₄CSe can be used as selenium ions supplier. But due to high cost and low stability of selenourea the first chalcogenizer is preferable.

ZnSe thin films deposition was carried out from the reaction mixture containing calculated volume of zinc chloride ZnCl₂, sodium citrate Na₃C₆H₅O₇, hydrochloric acid hydroxylamine NH₂OH · HCl and sodium hydroxide NaOH. Chalcogenizer was sodium selenosulfate Na₂SeSO₃. Synthesis temperature was 353 K, duration of the synthesis was 120 min, substrate material – sitall.

By using of energy-dispersive microanalysis of whole area of analyzed sample the concentration of main elements (Zn, Se) in freshly-deposited thin filmed selenide was determined. On electron microscopic image local areas in which analysis was carried out are shown.



| № | Elements , at. % | |
|---------|------------------|-------|
| | Zn | Se |
| 1 | 50,35 | 49,65 |
| 2 | 50,90 | 49,10 |
| 3 | 54,91 | 45,09 |
| 4 | 51,09 | 48,91 |
| 5 | 50,96 | 49,04 |
| Average | 51,64 | 48,36 |

The results of energy-dispersive analysis of ZnSe film obtained by chemical bath deposition from the reaction mixture, mol/L:
[ZnCl₂] = 0,03, [Na₃C₆H₅O₇] = 0,35, [NH₂OH · HCl] = 0,36, [NaOH] = 0,99, [Na₂SeSO₃] = 0,04.
Temperature – 353 K, duration of the synthesis – 120 min

As a result of EDX-analysis we should conclude that in deposited ZnSe layers there is no stoichiometry ratio between main elements: Zn and Se (51,64 and 48,36 at. %). Also, cracks are shown which are on the surface of analyzed chalcogenide film. It can be explained by mechanical tensions appearing in film due to difference in coefficients of thermal expansion of film and substrate: zinc selenide film $\alpha_{\text{ZnSe}} = 7,1 \cdot 10^{-6} \text{ K}^{-1}$ and sitall substrate $\alpha_{\text{sub}} = 5,0 \cdot 10^{-6} \text{ K}^{-1}$.